

SAMSUNG SEMICONDUCTOR INC

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**MMBA811C6**

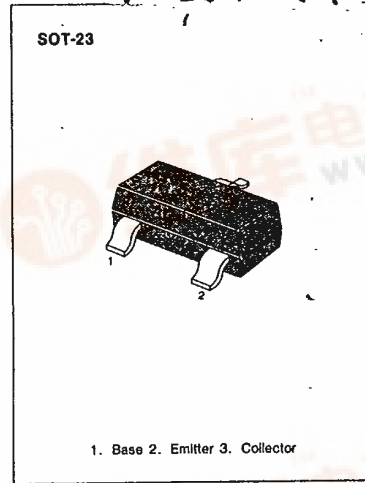
**PNP EPITAXIAL SILICON TRANSISTOR**

**DRIVER TRANSISTOR**

**ABSOLUTE MAXIMUM RATINGS (T<sub>a</sub> = 25°C)**

Characteristic	Symbol	Rating	Unit
Collector-Base Voltage	V <sub>CB0</sub>	50	V
Collector-Emitter Voltage	V <sub>CE0</sub>	45	V
Emitter-Base Voltage	V <sub>EB0</sub>	5	V
Collector Current	I <sub>c</sub>	50	mA
Collector Dissipation	P <sub>c</sub>	350	mW
Storage Temperature	T <sub>stg</sub>	150	°C

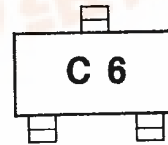
• Refer to MMBT5086 for graphs



**ELECTRICAL CHARACTERISTICS (T<sub>a</sub> = 25°C)**

Characteristic	Symbol	Test Condition	Min	Max	Unit
Collector-Base Breakdown Voltage	BV <sub>CB0</sub>	I <sub>c</sub> = 100μA, I <sub>E</sub> = 0	50		V
Collector-Emitter Breakdown Voltage	BV <sub>CE0</sub>	I <sub>c</sub> = 1.0mA, I <sub>B</sub> = 0	45		V
Emitter-Base Breakdown Voltage	BV <sub>EB0</sub>	I <sub>E</sub> = 10μA, I <sub>C</sub> = 0	5		V
Collector Cutoff Current	I <sub>CB0</sub>	V <sub>CB</sub> = 4.0V, I <sub>E</sub> = 0		50	nA
Emitter Cutoff Current	I <sub>EB0</sub>	V <sub>EB</sub> = 5.0V, I <sub>C</sub> = 0		50	nA
DC Current Gain	h <sub>FE</sub>	V <sub>CE</sub> = 3V, I <sub>C</sub> = 0.1mA	150		
		V <sub>CE</sub> = 3V, I <sub>C</sub> = 0.5mA	200		
Collector-Emitter Saturation Voltage	V <sub>CE(sat)</sub>	I <sub>C</sub> = 20mA, I <sub>B</sub> = 2.0mA		0.3	V
Current Gain-Bandwidth Product	f <sub>T</sub>	I <sub>C</sub> = 1.0mA, V <sub>CE</sub> = 6.0V f = 100MHz	75		MHz

Marking



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